

Notice of References Cited		Application/Control No. 10/580,560	Applicant(s)/Patent Under Reexamination KUDO ET AL.	
		Examiner XNNING NIU	Art Unit 2828	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2003/0021319	01-2003	Aoki, Masahiro	372/46
*	B US-4,740,987	04-1988	McCall et al.	372/96
*	C US-5,610,930	03-1997	Macomber et al.	372/36
*	D US-5,091,916	02-1992	Cimini et al.	372/96
*	E US-2003/0091080	05-2003	Aoyagi et al.	372/45
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
*	U	Itaya et al. "Low Threshold Current GaInAsP/InP DFB Laser," IEEE J. Quantum Electron, Vol. QE-23, NO. 6, June 1987, pp. 828-834.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.